

NOTES:

**FOR INFORMATION ONLY:  
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PARTS TO THIS DRAWING**

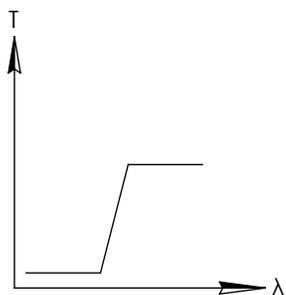
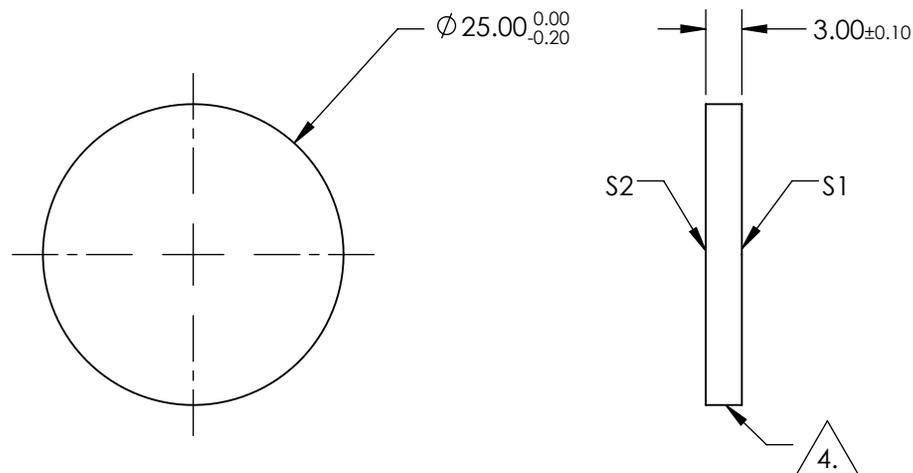
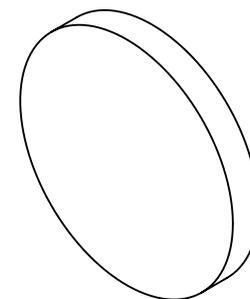
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 765 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 735nm @ 0° AOI  
 T(abs): =50% FOR 750±7.5nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT



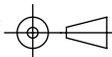
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 750nm, HIGH PERFORMANCE  
LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

66234

SHEET  
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

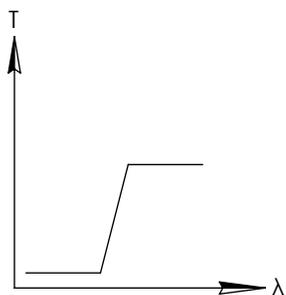
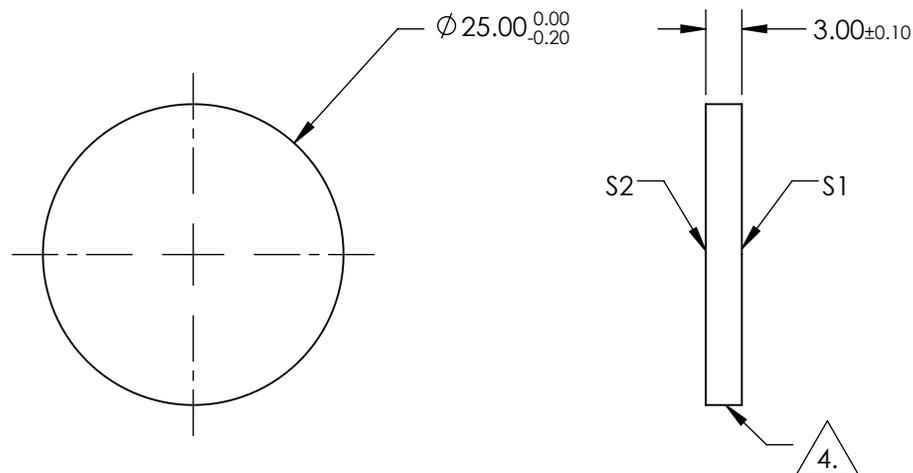
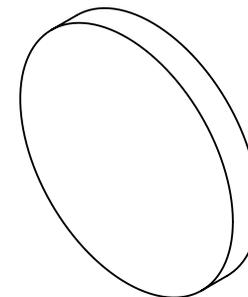
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 815 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 785nm @ 0° AOI  
 T(abs): =50% FOR 800±8nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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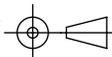
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 800nm, HIGH PERFORMANCE  
LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

66235

SHEET  
1 OF 1

NOTES:

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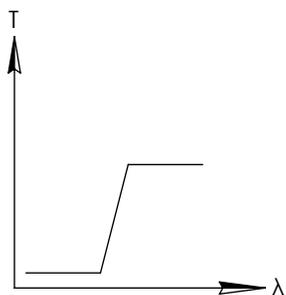
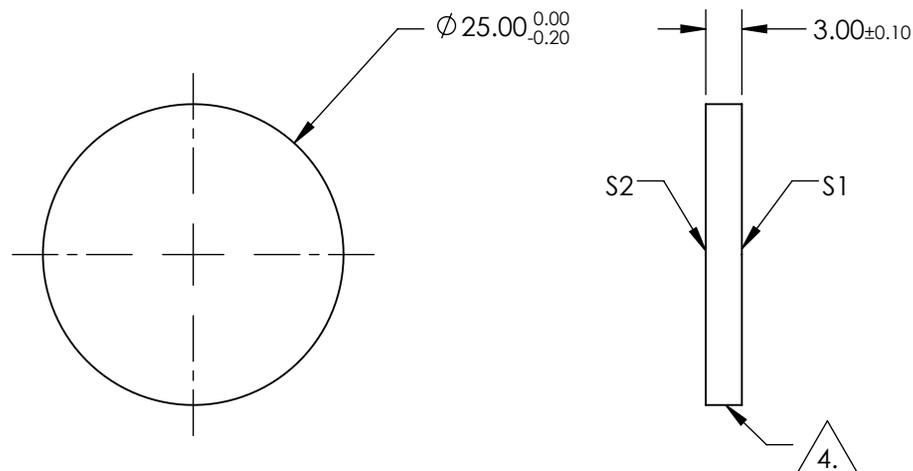
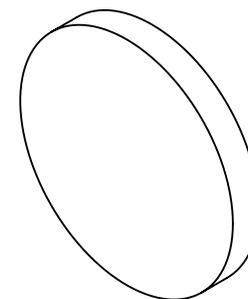
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 865 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 835nm @ 0° AOI  
 T(abs): =50% FOR 850±8.5nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT



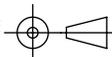
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 850nm, HIGH PERFORMANCE  
LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

66236

SHEET  
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

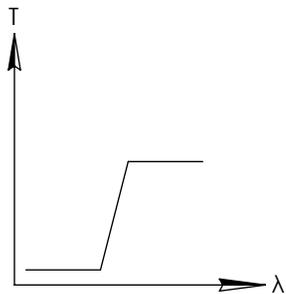
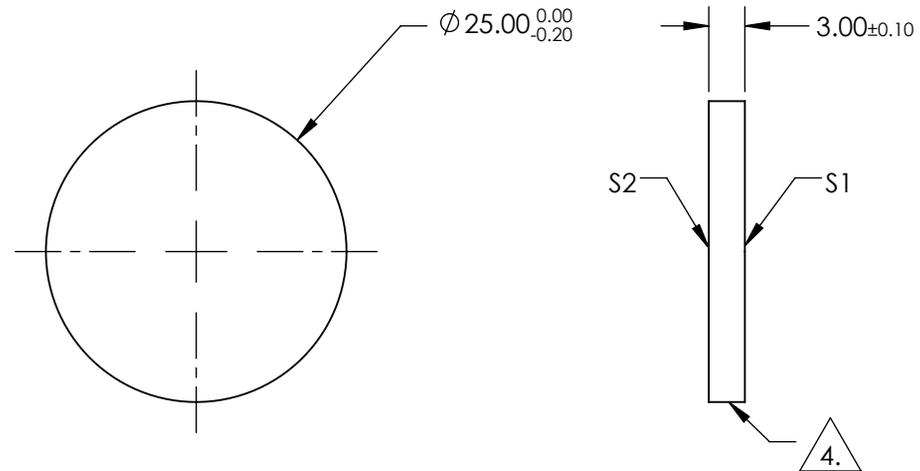
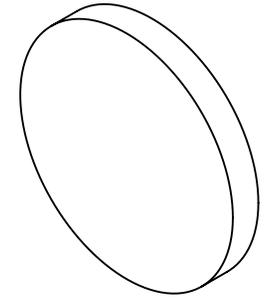
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 915 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 880nm @ 0° AOI  
 T(abs): =50% FOR 900±9nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:  
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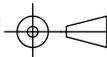
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 900nm, HIGH PERFORMANCE  
LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

66237

SHEET  
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

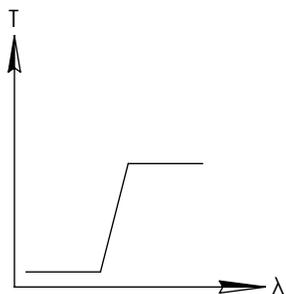
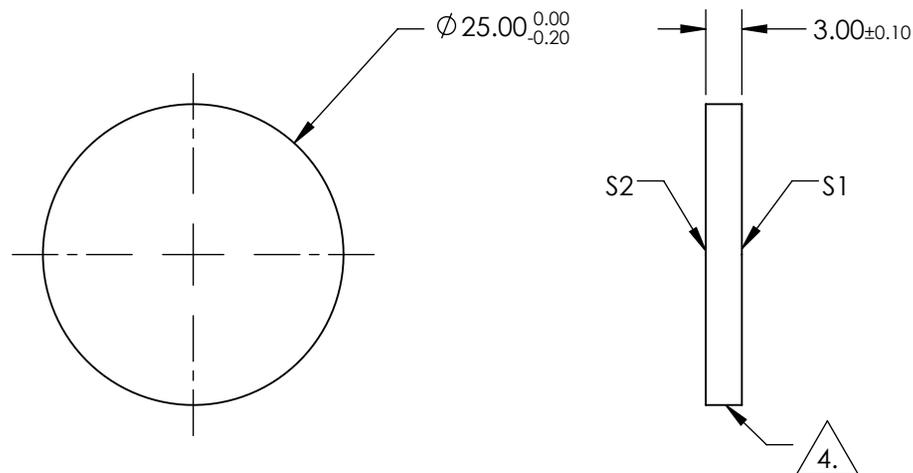
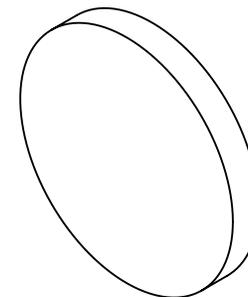
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 965 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 930nm @ 0° AOI  
 T(abs): =50% FOR 950±9.5nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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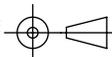
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
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REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 950nm, HIGH PERFORMANCE  
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

66238

SHEET  
 1 OF 1

NOTES:

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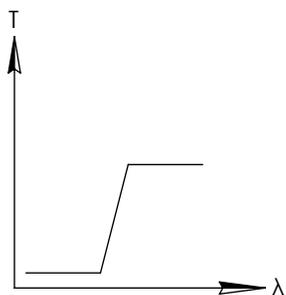
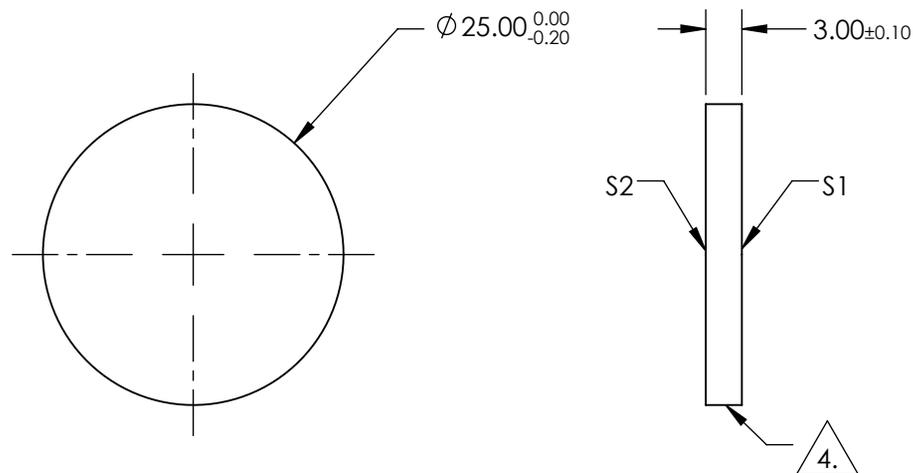
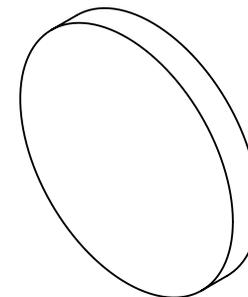
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 1020 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 980nm @ 0° AOI  
 T(abs): =50% FOR 1000±10nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT



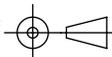
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
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REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 1000nm, HIGH PERFORMANCE  
LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

66239

SHEET  
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

S1: HARD DIELECTRIC SPUTTERED

T(avg): ≥91% FROM 1070 - 1650nm @ 0° AOI

T(avg): ≤0.01% FROM 200 - 1030nm @ 0° AOI

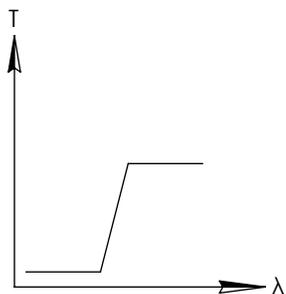
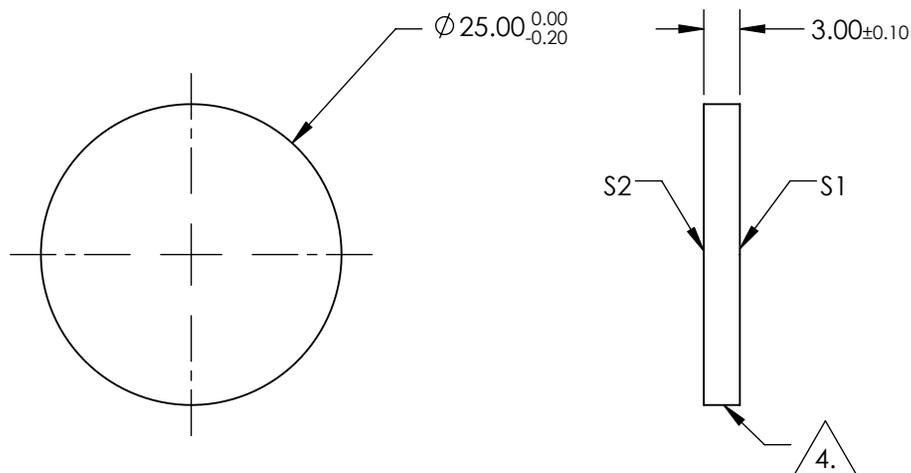
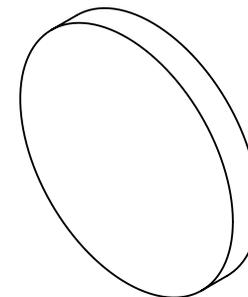
T(abs): =50% FOR 1050±10.5nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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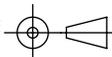


LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

THIRD ANGLE  
PROJECTION



ALL DIMS IN

mm

**EO**® Edmund Optics®

TITLE

Ø25mm, 1050nm, HIGH PERFORMANCE  
LONGPASS FILTER

DWG NO

66240

SHEET  
1 OF 1

NOTES:

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PARTS TO THIS DRAWING**

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

S1: HARD DIELECTRIC SPUTTERED

T(avg): ≥91% FROM 1120 - 1650nm @ 0° AOI

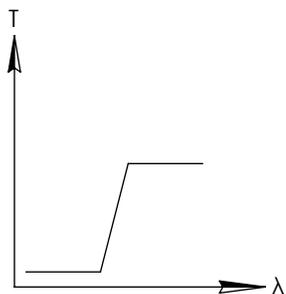
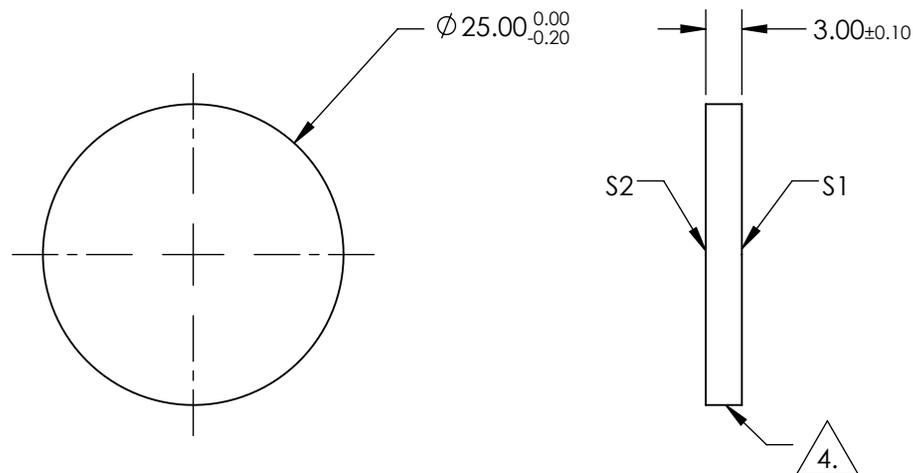
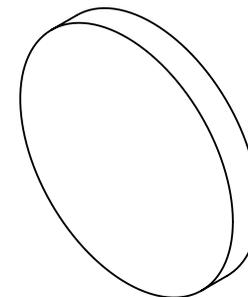
T(avg): ≤0.01% FROM 200 - 1080nm @ 0° AOI

T(abs): =50% FOR 1100±11nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT



LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 1100nm, HIGH PERFORMANCE  
LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

66241

SHEET  
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

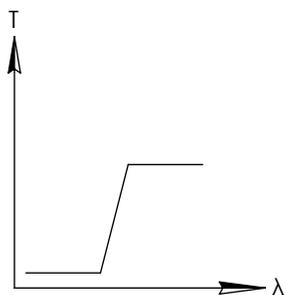
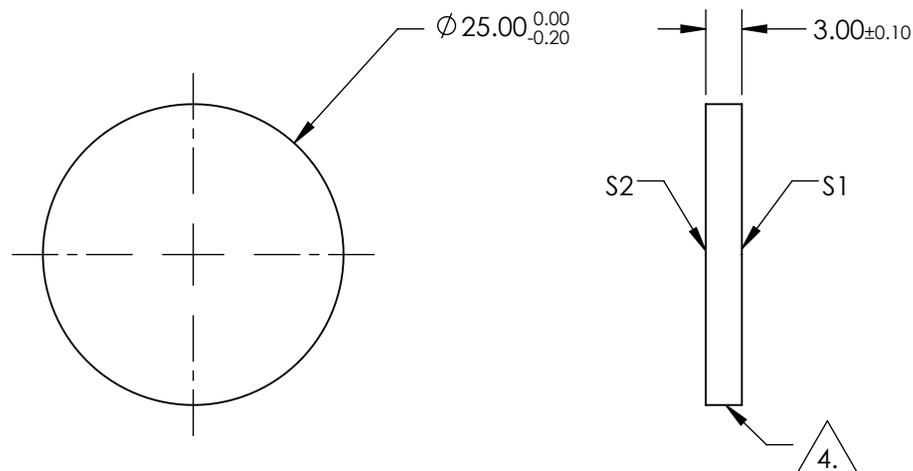
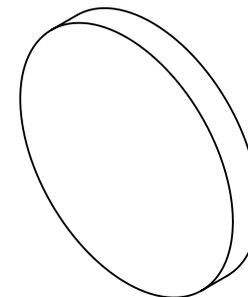
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 735 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 705nm @ 0° AOI  
 T(abs): =50% FOR 725±7.25nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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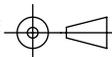
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
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REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 725nm, HIGH PERFORMANCE  
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

86068

SHEET  
 1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

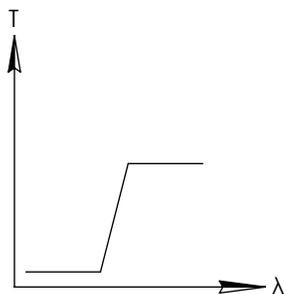
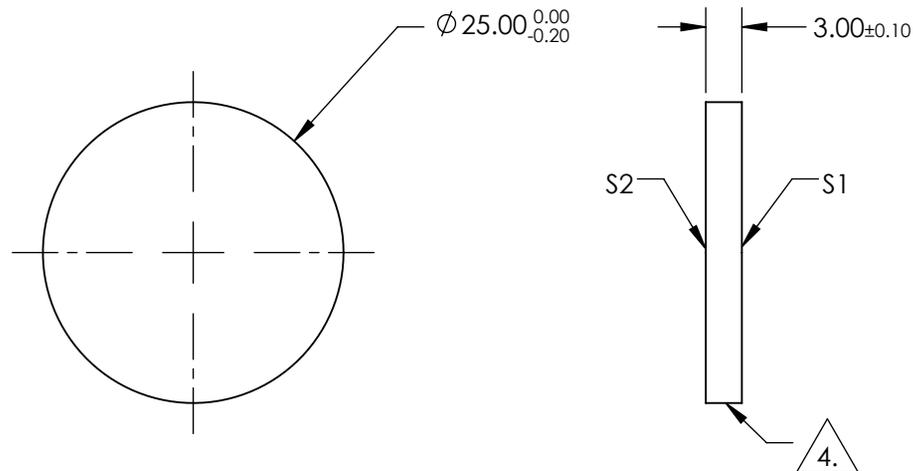
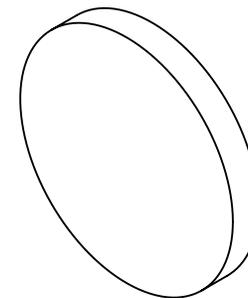
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 790 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 760nm @ 0° AOI  
 T(abs): =50% FOR 775±7.75nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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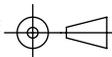
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 775nm, HIGH PERFORMANCE  
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

86069

SHEET  
 1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

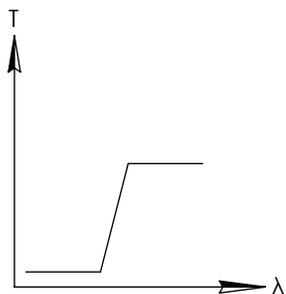
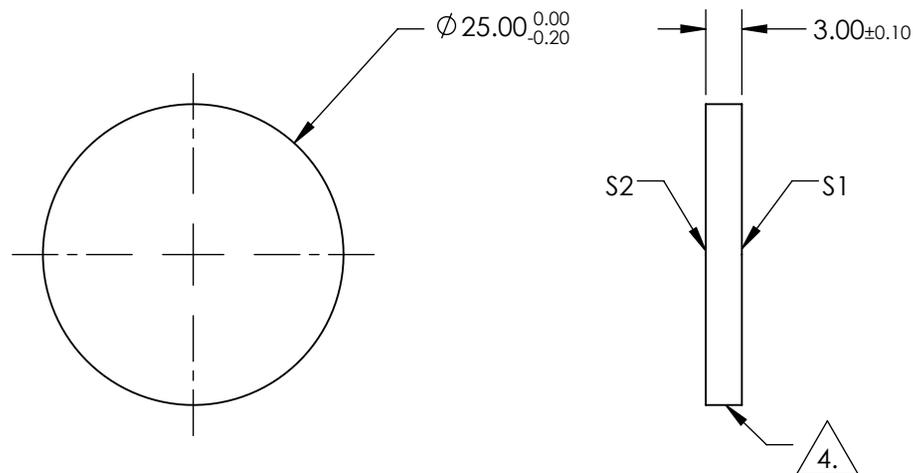
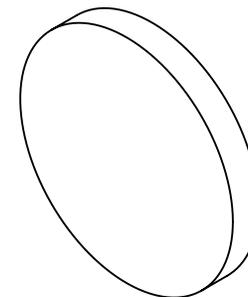
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 840 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 805nm @ 0° AOI  
 T(abs): =50% FOR 825±8.25nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

**FOR INFORMATION ONLY:  
DO NOT MANUFACTURE  
PARTS TO THIS DRAWING**



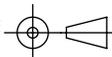
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 825nm, HIGH PERFORMANCE  
LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

86070

SHEET  
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

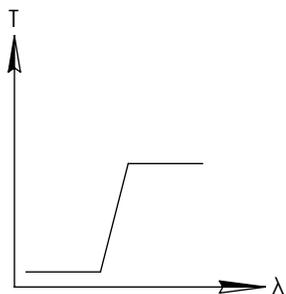
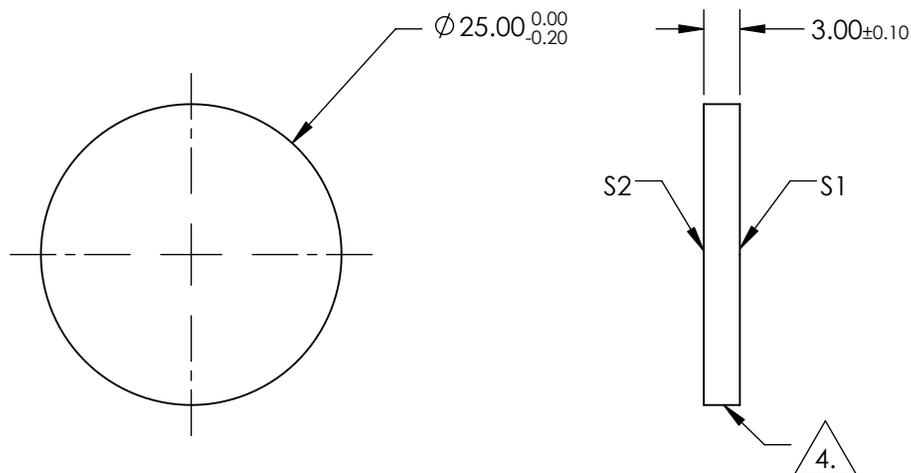
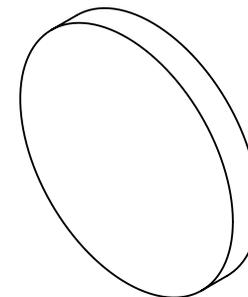
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 890 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 860nm @ 0° AOI  
 T(abs): =50% FOR 875±8.75nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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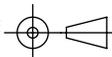
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 875nm, HIGH PERFORMANCE  
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

86071

SHEET  
 1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

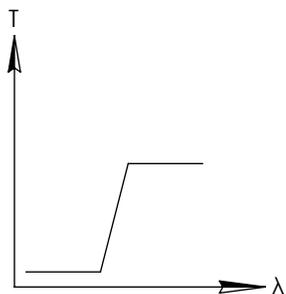
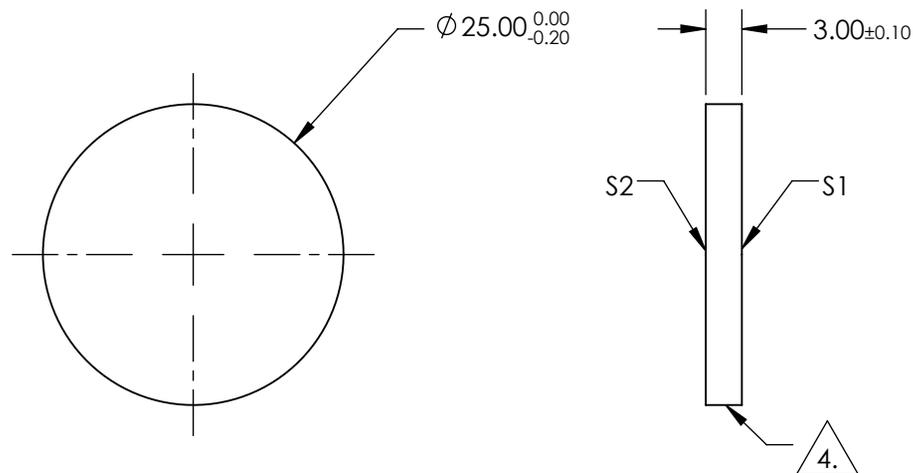
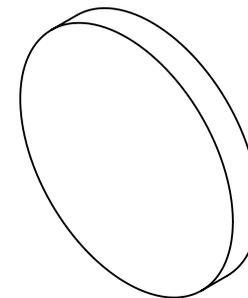
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 940 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 905nm @ 0° AOI  
 T(abs): =50% FOR 925±9.25nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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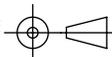
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
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REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 925nm, HIGH PERFORMANCE  
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

86072

SHEET  
 1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

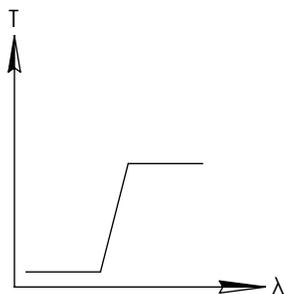
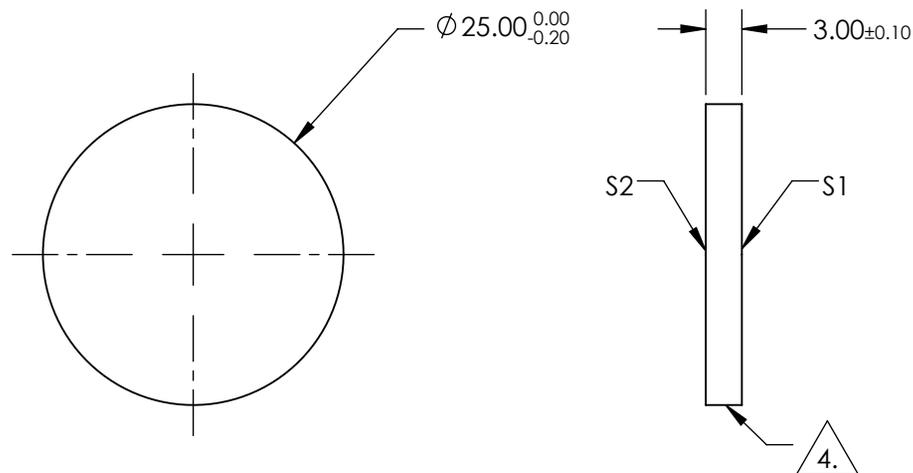
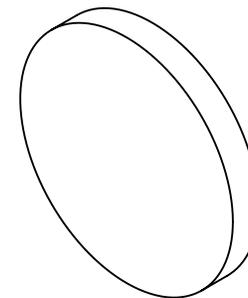
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 990 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 955nm @ 0° AOI  
 T(abs): =50% FOR 975±9.75nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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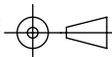
LONGPASS FILTER

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REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 975nm, HIGH PERFORMANCE  
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

86073

SHEET  
 1 OF 1

NOTES:

**FOR INFORMATION ONLY:  
DO NOT MANUFACTURE  
PARTS TO THIS DRAWING**

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

S1: HARD DIELECTRIC SPUTTERED

T(avg): ≥91% FROM 1045 - 1650nm @ 0° AOI

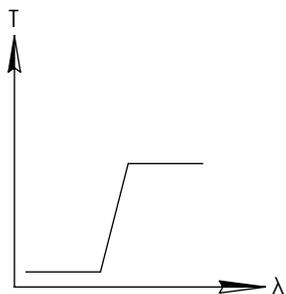
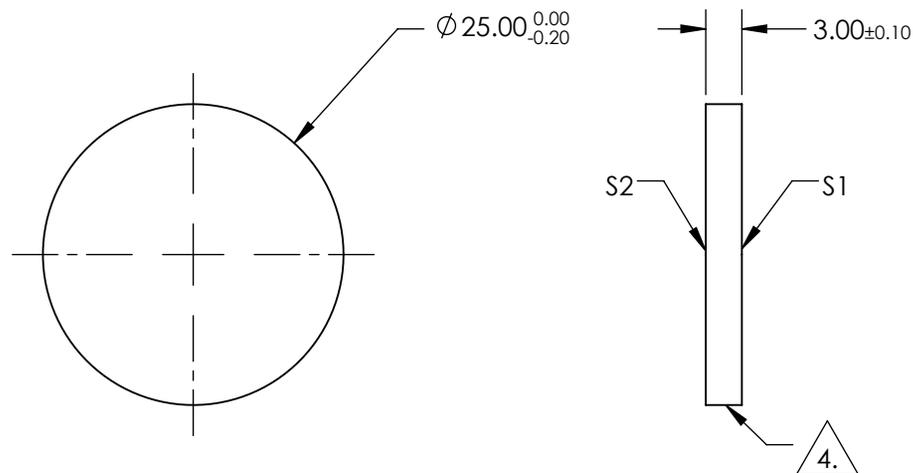
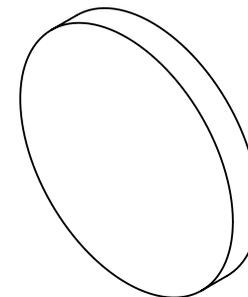
T(avg): ≤0.01% FROM 200 - 1005nm @ 0° AOI

T(abs): =50% FOR 1025±10.25nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

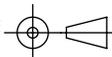


LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

THIRD ANGLE PROJECTION



ALL DIMS IN

mm

**EO**® Edmund Optics®

TITLE

Ø25mm, 1025nm, HIGH PERFORMANCE  
LONGPASS FILTER

DWG NO

86074

SHEET  
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

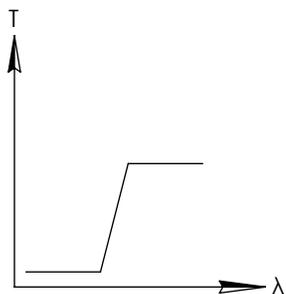
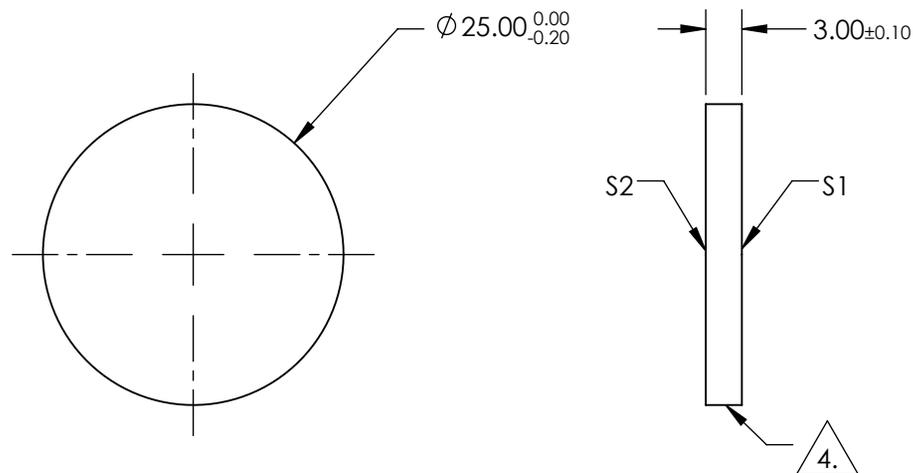
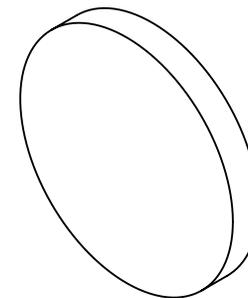
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 1095 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 1055nm @ 0° AOI  
 T(abs): =50% FOR 1075±10.75nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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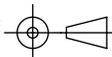
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
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REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 1075nm, HIGH PERFORMANCE  
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

86075

SHEET  
 1 OF 1